## Reexamination 10/709,345 VANCE, SCOTT LADELL Notice of References Cited Examiner Art Unit Page 1 of 1

Application/Control No.

Wen W. Huang 2618

Applicant(s)/Patent Under

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0018475 A1	01-2003	Basu et al.	704/270
*	В	US-3,746,789	07-1973	Alcivar, Ernesto A.	379/175
*	C	US-2007/0004464 A1	01-2007	Lair et al.	455/569.1
	D	US-			
	Ε	US-			
	F	US-			
	O	US-			
	Τ	US-			
		US-			
	7	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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